ISO 23729:2022-07 (E)

Surface chemical analysis - Atomic force microscopy - Guideline for restoration procedure for atomic force microscopy images dilated by finite probe size

Contents

Page

Foreword iv

Introduction v

1 Scope 1

2 Normative references 1

3 Terms and definitions 1

4 Symbols (and abbreviated terms) 3

5 Mathematical morphology modelling 3

6 Procedure of restoration of AFM topography images 4
6.1 General 4
6.2 Calibration of measuring systems 4
6.3 Environment requirements 5
6.4 Extraction of probe tip shape using certified reference materials 5
6.5 Estimation of probe tip shape by blind reconstruction 5
6.6 Reference materials 6
6.7 Probe shape characteristic and curvature radius 6
6.8 Validity test for topography image restoration 6

Annex A (informative) Example studies 7

Annex B (informative) Results of interlaboratory comparison 12

Bibliography 15